



- ★ Super Low Gate Charge
- ★ 100% EAS Guaranteed
- ★ Green Device Available
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology

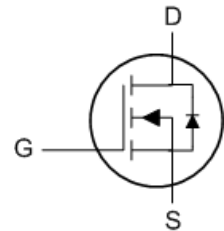
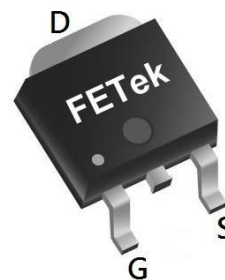
Product Summary

| BVDSS | RDSON | ID |
|-------|-------|-----|
| 60V | 8.5mΩ | 75A |

Description

The FKD6032A is the high cell density trenched N-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The FKD6032A meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

TO252 Pin Configuration

Absolute Maximum Ratings

| Symbol | Parameter | Rating | Units |
|------------------------|--|------------|-------|
| V_{DS} | Drain-Source Voltage | 60 | V |
| V_{GS} | Gate-Source Voltage | ±20 | V |
| $I_D@T_C=25^{\circ}C$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 75 | A |
| $I_D@T_C=100^{\circ}C$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 47 | A |
| I_{DM} | Pulsed Drain Current ² | 280 | A |
| EAS | Single Pulse Avalanche Energy ³ | 80 | mJ |
| I_{AS} | Avalanche Current | 40 | A |
| $P_D@T_C=25^{\circ}C$ | Total Power Dissipation ⁴ | 41 | W |
| T_{STG} | Storage Temperature Range | -55 to 150 | °C |
| T_J | Operating Junction Temperature Range | -55 to 150 | °C |

Thermal Data

| Symbol | Parameter | Typ. | Max. | Unit |
|-----------------|--|------|------|------|
| $R_{\theta JA}$ | Thermal Resistance Junction-ambient ¹ | --- | 62 | °C/W |
| $R_{\theta JC}$ | Thermal Resistance Junction-case ¹ | --- | 1.4 | °C/W |

**Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)**

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|--------------|--|--|------|------|-----------|------------|
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{GS}=0V, I_D=250\mu A$ | 60 | --- | --- | V |
| $R_{DS(ON)}$ | Static Drain-Source On-Resistance ² | $V_{GS}=10V, I_D=20A$ | --- | 7.1 | 8.5 | m Ω |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{GS}=V_{DS}, I_D=250\mu A$ | 2.2 | --- | 4.5 | V |
| I_{DSS} | Drain-Source Leakage Current | $V_{DS}=48V, V_{GS}=0V, T_J=25^\circ\text{C}$ | --- | --- | 1 | μA |
| | | $V_{DS}=48V, V_{GS}=0V, T_J=55^\circ\text{C}$ | --- | --- | 5 | |
| I_{GSS} | Gate-Source Leakage Current | $V_{GS}=\pm 20V, V_{DS}=0V$ | --- | --- | ± 100 | nA |
| R_g | Gate Resistance | $V_{DS}=0V, V_{GS}=0V, f=1\text{MHz}$ | --- | 1.2 | --- | Ω |
| Q_g | Total Gate Charge (10V) | $V_{DS}=30V, V_{GS}=10V, I_D=18A$ | --- | 57 | --- | nC |
| Q_{gs} | Gate-Source Charge | | --- | 8.7 | --- | |
| Q_{gd} | Gate-Drain Charge | | --- | 14 | --- | |
| $T_{d(on)}$ | Turn-On Delay Time | $V_{DD}=30V, V_{GS}=10V, R_G=3.3\Omega, I_D=20A$ | --- | 16.2 | --- | ns |
| T_r | Rise Time | | --- | 41.2 | --- | |
| $T_{d(off)}$ | Turn-Off Delay Time | | --- | 56.4 | --- | |
| T_f | Fall Time | | --- | 16.2 | --- | |
| C_{iss} | Input Capacitance | $V_{DS}=30V, V_{GS}=0V, f=1\text{MHz}$ | --- | 3307 | --- | μF |
| C_{oss} | Output Capacitance | | --- | 201 | --- | |
| C_{rss} | Reverse Transfer Capacitance | | --- | 151 | --- | |

Diode Characteristics

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|----------|--|---|------|------|------|------|
| I_S | Continuous Source Current ^{1,5} | $V_G=V_D=0V$, Force Current | --- | --- | 75 | A |
| V_{SD} | Diode Forward Voltage ² | $V_{GS}=0V, I_S=1A, T_J=25^\circ\text{C}$ | --- | --- | 1.2 | V |
| t_{rr} | Reverse Recovery Time | $I_F=20A, di/dt=100A/\mu s, T_J=25^\circ\text{C}$ | --- | 22 | --- | nS |
| Q_{rr} | Reverse Recovery Charge | | --- | 72 | --- | nC |

Note :

- The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- The data tested by pulsed, pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- The EAS data shows Max. rating. The test condition is $V_{DD}=50V, V_{GS}=10V, L=0.1mH, I_{AS}=40A$
- The power dissipation is limited by 150 $^\circ\text{C}$ junction temperature
- The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.

Typical Characteristics

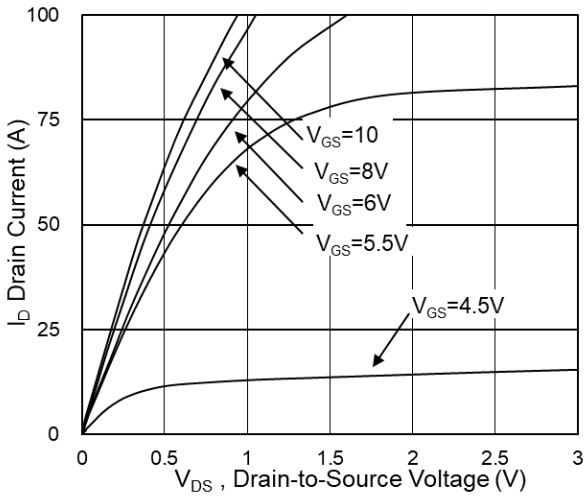


Fig.1 Typical Output Characteristics

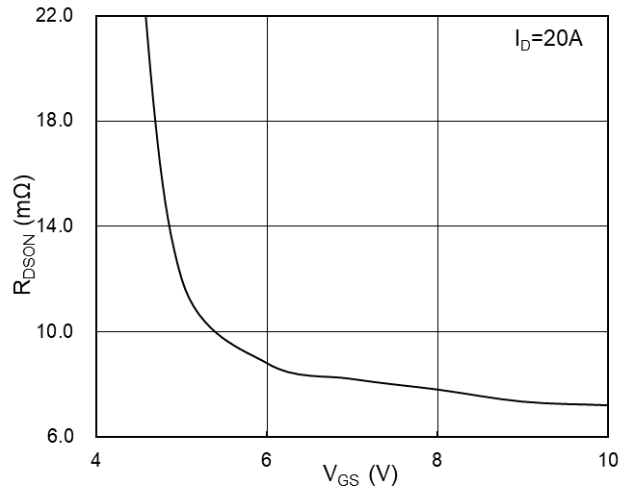


Fig.2 On-Resistance vs G-S Voltage

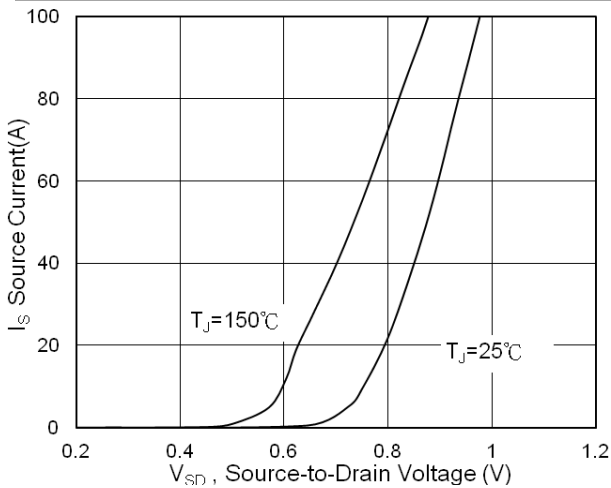


Fig.3 Source Drain Forward Characteristics

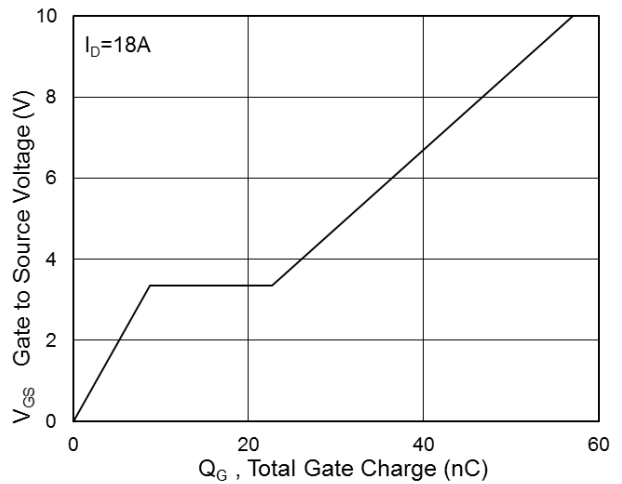


Fig.4 Gate-Charge Characteristics

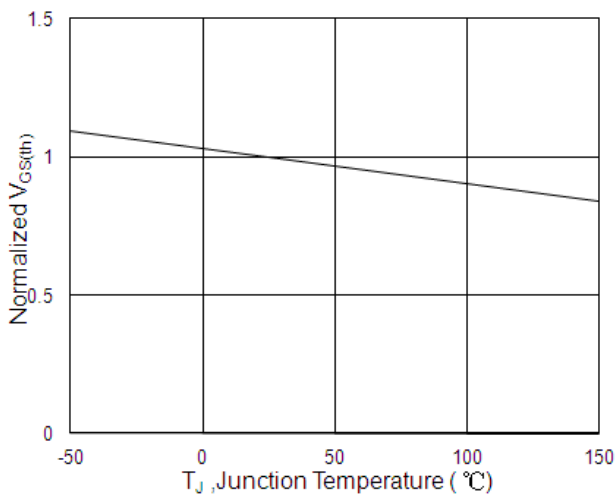


Fig.5 Normalized $V_{GS(th)}$ vs T_J

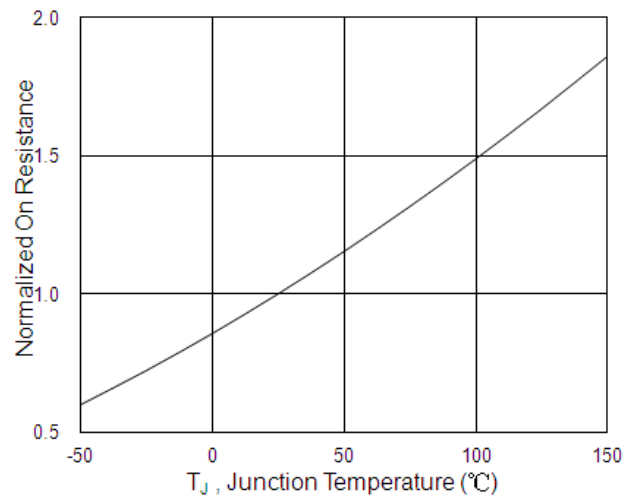


Fig.6 Normalized R_{DSON} vs T_J

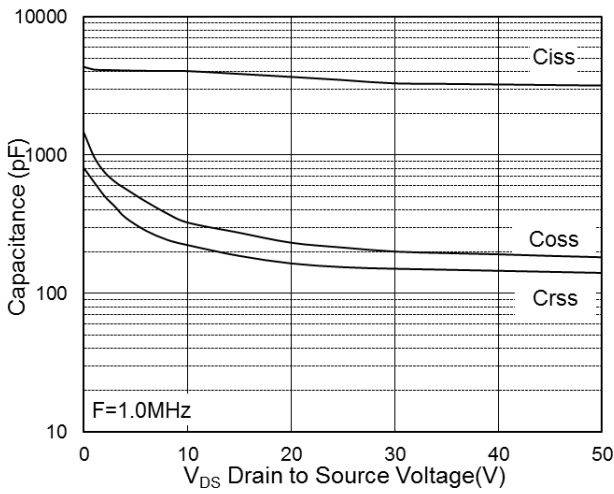


Fig.7 Capacitance

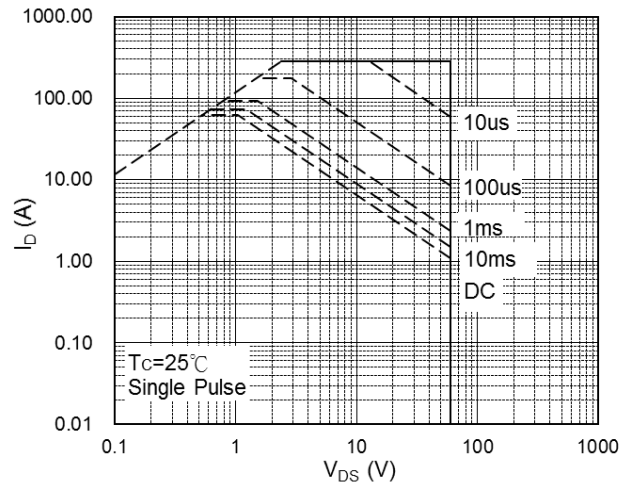


Fig.8 Safe Operating Area

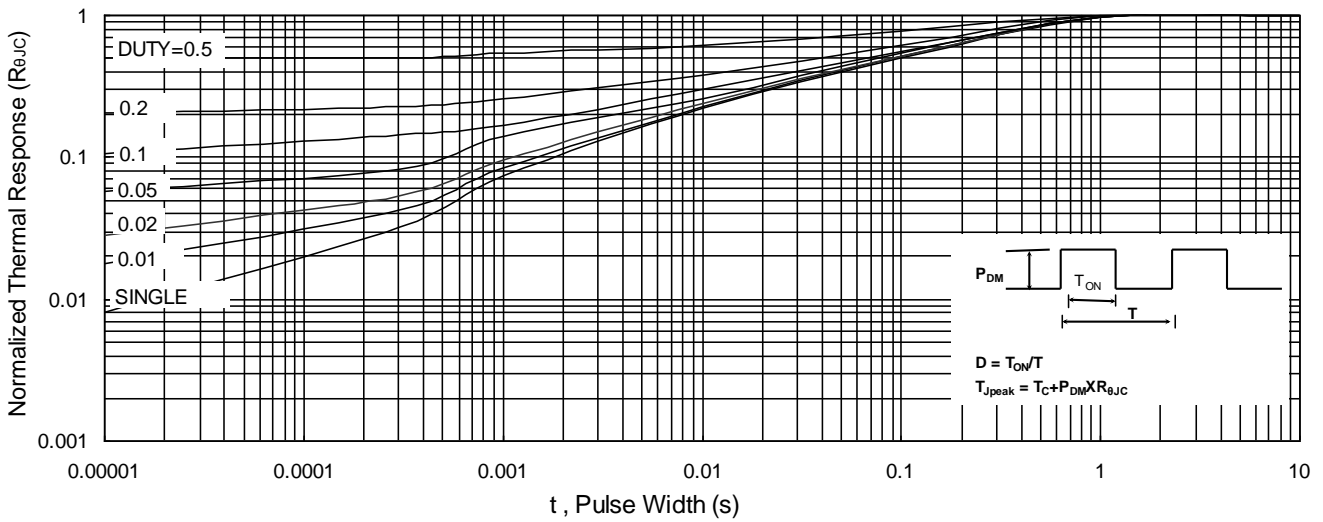


Fig.9 Normalized Maximum Transient Thermal Impedance

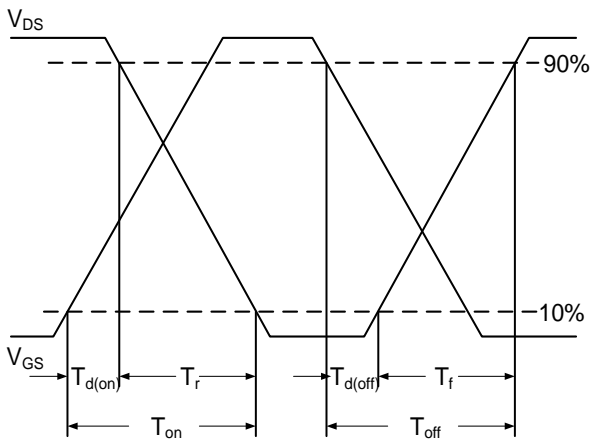


Fig.10 Switching Time Waveform

$$EAS = \frac{1}{2} L \times I_{AS}^2 \times \frac{BV_{DSS}}{BV_{DSS} - V_{DD}}$$

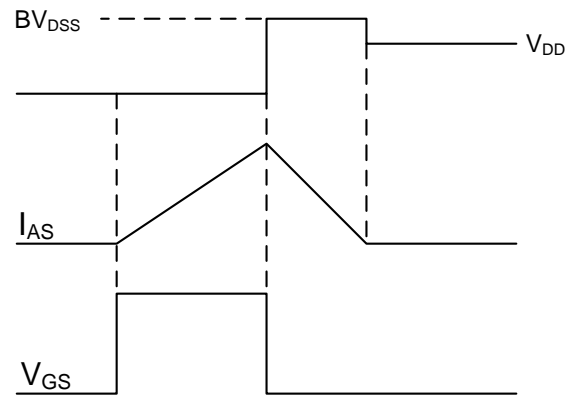


Fig.11 Unclamped Inductive Switching Waveform